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CASE PP/1-22826/A/CGC 2139

CERTIFICATE OF MAILING

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to the: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Anna R. Maddalena
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7/22/04
Date

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF

Group Art Unit: 1751

HUI CHIN ET AL

Examiner:

APPLICATION NO: 10/761,821

FILED: JANUARY 21, 2004

FOR: ANTISTATIC COMPOSITION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 CFR 1.56, Applicants wish to call the Examiner's attention to the references cited on the attached form PTO-1449.

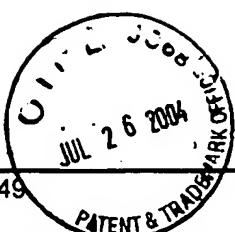
Copies of these references are enclosed herewith.

The Examiner is requested to consider the foregoing information in relation to this application and indicate that each reference was considered by returning a copy of the initialed PTO 1449 form.

Respectfully submitted,

Tyler A. Stevenson
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Encl. References
PTO-1449 Form



Sheet 1 of 1.

FORM PTO-1449 PATENT & TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)		Docket Number (Optional) PP/1-22826/A/CGC 2139	Application Number 10/761,821
		Applicant HUI CHIN ET AL	
		Filing Date JANUARY 21, 2004	Group Art Unit 1751

U. S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
	2000226749	8/00	Japan			✓	
	2000212836	8/00	Japan			✓	
	2000212834	8/00	Japan			✓	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

	English language abstract for JP 2000226749 (2000)
	English language abstract for JP 2000212836 (2000)
	English language abstract for JP 2000212834 (2000)

EXAMINER	DATE CONSIDERED
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